



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

American Calibration Inc.

**4410 Route 176, Suite 11
Crystal Lake, IL 60014**

Fulfills the requirements of

ISO/IEC 17025:2017

and national standard

ANSI/NCSL Z540-1-1994 (R2002)

In the fields of

**CALIBRATION, DIMENSIONAL MEASUREMENT and
TESTING**

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

A handwritten signature in black ink, appearing to be 'J. Stine', is positioned above a horizontal line.

Jason Stine, Vice President
Expiry Date: 06 August 2026
Certificate Number: ACT-1886



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

AND

ANSI/NCSL Z540-1-1994 (R2002)

American Calibration Inc.

4410 Route 176, Suite 11
 Crystal Lake, IL 60014
 Jimmy McGue 815-356-5839

CALIBRATION, DIMENSIONAL MEASUREMENT, AND TESTING

Valid to: **August 6, 2026**

Certificate Number: **ACT-1886**

CALIBRATION

Acoustics and Vibration

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Accelerometer ¹ Voltage Sensitivity – Frequency Response (100 mV/g) (Up to 800 g payload)	7 Hz to 10 Hz 7 Hz to 30 Hz (30 to 2000) Hz (2 to 10) kHz	7.44 % of reading 5 % of reading 6.09 % of reading 7.21 % of reading	Accelerometer Calibrator, Reference Accelerometer Utilizing Back-to-Back Method
Sound Level Meters ¹	1 kHz 94 dB 114 dB	0.76 dB 0.76 dB	Comparison to Acoustic Calibrator

Chemical Quantities

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
pH Meters ^{1,7}	4 pH 7 pH 10 pH 12 pH	0.017 pH 0.023 pH 0.052 pH 0.045 pH	Comparison to Accredited pH Solutions
Conductivity Meters ^{1,7}	10 µS/cm 100 µS/cm 1 000 µS/cm 1 400 µS/cm 10 000 µS/cm 100 mS/cm	0.65 µS/cm 2.9 µS/cm 20 µS/cm 28 µS/cm 0.19 mS/cm 1.8 mS/cm	Comparison to Accredited Conductivity Solutions

Chemical Quantities

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Refractometers ^{1,7}	(10 to 60) °Bx	0.94 °Bx	Comparison to Reference Sucrose Solutions
Viscosity ^{1,7}	500 cP	39 cP	Comparison to Reference Viscosity Solution
Carbon Dioxide (CO ₂) Analyzers ^{1,7} CO ₂ Concentration in Gas	0 % CO ₂ 5 % CO ₂ 20 % CO ₂	0.26 % CO ₂ 0.17 % CO ₂ 0.59 % CO ₂	Comparison to Vaisala GMP221 CO ₂ Sensor

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Current – Measure ¹	Up to 10 µA (10 to 100) µA (0.1 to 1) mA (1 to 10) mA (10 to 100) mA (0.1 to 1) A (1 to 10) A (10 to 30) A	26 pA/µA + 0.42 nA 10 pA/µA + 0.41 nA 9.5 nA/mA + 4.3 nA 14 nA/mA + 42 nA 57 nA/mA + 1 µA 0.13 mA/A + 0.1 mA 0.24 mA/A + 0.41 mA 0.55 mA/A + 4.4 mA	Comparison to Fluke 8588A Reference Multimeter
DC Current – Source ¹	(0 to 220) µA (0.22 to 2.2) mA (2.2 to 22) mA (22 to 220) mA (0.22 to 2.2) A	55 pA/µA + 6 nA 38 nA/mA + 7 nA 41 nA/mA + 40 nA 57 nA/mA + 0.7 µA 0.1 mA/A + 12 µA	Comparison to Fluke 5730A Multiproduct Calibrator
DC Current – Source ^{1,2}	Up to 120 µA (0.12 to 1.2) mA (1.2 to 12) mA (12 to 120) mA (0.12 to 1.2) A (1.2 to 3.1) A (3.1 to 12) A (12 to 30.2) A	98 pA/µA + 5 nA 83 nA/mA + 12 nA 80 nA/mA + 63 nA 79 nA/mA + 0.63 µA 0.12 mA/A + 8 µA 0.23 mA/A + 12 µA 0.23 mA/A + 0.2 mA 0.8 mA/A + 0.39 mA	Comparison to Fluke 5560A Multiproduct Calibrator

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Clamp-on Meters ¹	(12 to 1 000) A	24.5 mA/A + 0.5 A	Comparison to Fluke 5502A Multiproduct Calibrator, 50-turn Coil
AC Current – Measure ¹	Up to 1 A (3 to 5) Hz (5 to 10) Hz 10 Hz to 5 kHz (1 to 3) A (3 to 5) Hz (5 to 10) Hz 10 Hz to 5 kHz	12 mA 40 mA 1.8 mA 40 mA 14 mA 8.5 mA	Comparison to Keysight 34401A 6.5 Digit Multimeter
AC Current – Measure ¹	(3 to 5) A (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz	17.3 mA/A + 2.8 mA 9.3 mA/A + 3 mA 4.9 mA/A + 6.6 mA	Comparison to Fluke 289 Digital Multimeter
AC Current – Measure ¹	(5 to 10) A (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz	17.3 mA/A + 6.3 mA 9.3 mA/A + 6.6 mA 4.9 mA/A + 12 mA	Comparison to Fluke 289 Digital Multimeter
Magnetic Inspection Unit ¹ AC Current – Measure	(500 to 10 000) A	15 A/kA + 13 A	Comparison to Ammeter, Current Shunt
AC Current – Source ¹	(9 to 220) μ A (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (0.22 to 2.2) mA (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (2.2 to 22) mA (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	0.28 nA/ μ A + 16 nA 0.19 nA/ μ A + 10 nA 0.11 nA/ μ A + 8 nA 0.35 nA/ μ A + 12 nA 1.2 nA/ μ A + 65 nA 0.29 μ A/mA + 40 nA 0.19 μ A/mA + 35 nA 0.12 μ A/mA + 35 nA 0.25 μ A/mA + 0.11 μ A 1.3 μ A/mA + 0.65 μ A 0.29 μ A/mA + 0.4 μ A 0.19 μ A/mA + 0.35 μ A 0.12 μ A/mA + 0.35 μ A 0.25 μ A/mA + 0.55 μ A 1.3 μ A/mA + 5 μ A	Comparison to Fluke 5730A Multiproduct Calibrator



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Source ¹	(22 to 220) mA (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (0.22 to 2.2) A (20 to 1 000) Hz (1 to 5) kHz (5 to 10) kHz	0.29 μ A/mA + 4 μ A 0.16 μ A/mA + 3.5 μ A 0.13 μ A/mA + 2.5 μ A 0.24 μ A/mA + 3.5 μ A 1.3 μ A/mA + 10 μ A 0.32 mA/A + 35 μ A 0.55 mA/A + 80 μ A 7.9 mA/A + 0.16 mA	Comparison to Fluke 5730A Multiproduct Calibrator
AC Current – Source ^{1,2}	Up to 120 μ A (3 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz (0.12 to 1.2) mA (3 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz (1.2 to 12) mA (3 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz (12 to 120) mA (3 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.2 nA/ μ A + 8 nA 0.2 nA/ μ A + 8 nA 0.2 nA/ μ A + 8 nA 1.3 nA/ μ A + 31 nA 4 nA/ μ A + 1 μ A 0.2 μ A/mA + 0.1 μ A 0.2 μ A/mA + 0.1 μ A 0.2 μ A/mA + 0.1 μ A 1.3 μ A/mA + 0.1 μ A 4 μ A/mA + 4 μ A 0.2 μ A/mA + 0.8 μ A 0.2 μ A/mA + 0.8 μ A 0.2 μ A/mA + 1 μ A 1.3 μ A/mA + 1 μ A 4 μ A/mA + 8 μ A 0.2 μ A/mA + 8 μ A 0.2 μ A/mA + 4 μ A 0.2 μ A/mA + 7 μ A 1.3 μ A/mA + 8 μ A 4 μ A/mA + 78 μ A	Comparison to Fluke 5560A Multiproduct Calibrator

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Source ^{1,2}	(0.12 to 1.2) A		Comparison to Fluke 5560A Multiproduct Calibrator
	(3 to 45) Hz	0.19 mA/A + 78 μA	
	45 Hz to 1 kHz	0.19 mA/A + 39 μA	
	(1 to 5) kHz	0.19 mA/A + 63 μA	
	(5 to 10) kHz	1.9 mA/A + 0.24 mA	
	(10 to 30) kHz	3.9 mA/A + 0.24 mA	
	(1.2 to 3.1) A		
	(3 to 45) Hz	0.3 mA/A + 0.38 mA	
	45 Hz to 1 kHz	0.3 mA/A + 0.24 mA	
	(1 to 5) kHz	0.3 mA/A + 0.24 mA	
	(5 to 10) kHz	2 mA/A + 0.38 mA	
	(3.1 to 12) A		
	(3 to 45) Hz	0.3 mA/A + 0.78 mA	
	45 Hz to 1 kHz	0.3 mA/A + 0.38 mA	
	(1 to 5) kHz	0.3 mA/A + 0.62 mA	
(5 to 10) kHz	2 mA/A + 0.78 mA		
(12 to 30.2) A			
(3 to 45) Hz	0.8 mA/A + 7.8 mA		
45 Hz to 1 kHz	0.6 mA/A + 6.2 mA		
(1 to 5) kHz	4 mA/A + 6.2 mA		
AC Clamp-on Meters ¹	60 Hz (12 to 1 000) A	6.1 mA/A + 0.52 A	Comparison to Fluke 5502A Multiproduct Calibrator, 50-turn Coil
Resistance – Source ¹ (Fixed Artifacts)	0.1 mΩ	58 nΩ	Comparison to Precision Resistance Standard
	1 mΩ	0.58 μΩ	
	10 mΩ	5.8 μΩ	
	100 mΩ	58 μΩ	
Resistance – Source ¹ (Fixed Artifacts)	500 kΩ	5.8 kΩ	Comparison to Resistance Test Box
	1 MΩ	12 kΩ	
	5 MΩ	58 kΩ	
	10 MΩ	0.12 MΩ	
	25 MΩ	0.29 MΩ	
	50 MΩ	0.58 MΩ	
	100 MΩ	1.2 MΩ	
	500 MΩ	5.8 MΩ	
	1 GΩ	12 MΩ	
	2 GΩ	25 MΩ	
	50 GΩ	0.58 GΩ	
	100 GΩ	1.2 GΩ	
200 GΩ	2.3 GΩ		



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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Resistance – Source ¹ (Synthesized-Fixed)	1 Ω	0.11 mΩ	Comparison to Fluke 5730A Multiproduct Calibrator
	1.9 Ω	0.11 mΩ	
	10 Ω	28 μΩ	
	19 Ω	29 μΩ	
	100 Ω	12 μΩ	
	190 Ω	12 μΩ	
	1 kΩ	7.7 mΩ	
	1.9 kΩ	7.9 mΩ	
	10 kΩ	7.7 mΩ	
	19 kΩ	7.9 mΩ	
	100 kΩ	10 mΩ	
	190 kΩ	10 mΩ	
	1 MΩ	16 Ω	
	1.9 MΩ	22 Ω	
10 MΩ	47 Ω		
19 MΩ	68 Ω		
100 MΩ	0.15 kΩ		
Resistance – Source ^{1,2} (Synthesized-Fixed)	Up to 12 Ω	21 μΩ/Ω + 0.8 mΩ	Comparison to Fluke 5560A Multiproduct Calibrator
	(12 to 120) Ω	20 μΩ/Ω + 0.8 mΩ	
	(0.12 to 1.2) kΩ	20 mΩ/kΩ + 1.6 mΩ	
	(1.2 to 12) kΩ	20 mΩ/kΩ + 16 mΩ	
	(12 to 120) kΩ	20 mΩ/kΩ + 0.16 Ω	
	(0.12 to 1.2) MΩ	20 Ω/MΩ + 10 mΩ	
	(1.2 to 12) MΩ	28 Ω/MΩ + 30 mΩ	
	(12 to 120) MΩ	0.33 kΩ/MΩ + 2 kΩ	
(120 to 1 200) MΩ	3.2 Ω/MΩ + 78 kΩ		
Resistance – Measure ¹	Up to 1 Ω	17 μΩ/Ω + 4 μΩ	Comparison to Fluke 8588A Reference Multimeter
	(1 to 10) Ω	11 μΩ/Ω + 14 μΩ	
	(10 to 100) Ω	9.2 μΩ/Ω + 54 μΩ	
	100 Ω to 1 kΩ	9.2 μΩ/Ω + 0.49 mΩ	
	(1 to 10) kΩ	9.3 μΩ/Ω + 4.9 mΩ	
	(10 to 100) kΩ	9.5 μΩ/Ω + 49 mΩ	
	100 kΩ to 1 MΩ	11 μΩ/Ω + 0.92 Ω	
	(1 to 10) MΩ	20 μΩ/Ω + 99 Ω	
	(10 to 100) MΩ	0.12 mΩ/Ω + 10 kΩ	
	100 MΩ to 1 GΩ	1.3 mΩ/Ω + 1 MΩ	



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of RTD Indicating Devices – Source ^{1,2}	Pt 385, 100 Ω		Comparison to Fluke 7526A Precision Process Calibrator
	(-200 to -80) °C	0.013 °C	
	(-80 to 0) °C	0.02 °C	
	(0 to 100) °C	0.02 °C	
	(100 to 300) °C	0.024 °C	
	(300 to 400) °C	0.026 °C	
	(400 to 630) °C	0.033 °C	
	(630 to 800) °C	0.038 °C	
	Pt 3926, 100 Ω		
	(-200 to -80) °C	0.013 °C	
	(-80 to 0) °C	0.015 °C	
	(0 to 100) °C	0.017 °C	
	(100 to 300) °C	0.022 °C	
	(200 to 400) °C	0.026 °C	
	(400 to 630) °C	0.032 °C	
	Pt 3916, 100 Ω		
	(-200 to -190) °C	0.01 °C	
	(-190 to -80) °C	0.013 °C	
	(-80 to 0) °C	0.015 °C	
	(0 to 100) °C	0.017 °C	
	(100 to 300) °C	0.022 °C	
	(300 to 400) °C	0.026 °C	
	(400 to 600) °C	0.031 °C	
	(600 to 630) °C	0.033 °C	
Pt 385, 200 Ω			
(-200 to -80) °C	0.053 °C		
(-80 to 0) °C	0.056 °C		
(0 to 100) °C	0.06 °C		
(100 to 260) °C	0.06 °C		
(260 to 300) °C	0.069 °C		
(300 to 400) °C	0.071 °C		
(400 to 630) °C	0.088 °C		

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of RTD Indicating Devices – Source ^{1,2}	Pt 385, 500 Ω		Comparison to Fluke 7526A Precision Process Calibrator
	(-200 to 0) °C	0.025 °C	
	(0 to 100) °C	0.028 °C	
	(100 to 300) °C	0.034 °C	
	(300 to 400) °C	0.038 °C	
	(400 to 630) °C	0.045 °C	
	Pt 385, 1 000 Ω		
	(-200 to 0) °C	0.015 °C	
	(0 to 100) °C	0.018 °C	
	(100 to 300) °C	0.024 °C	
	(300 to 400) °C	0.026 °C	
	(400 to 630) °C	0.033 °C	
Ni 120, 120 Ω			
(-80 to 260) °C	0.009 °C		
Cu 427, 10 Ω			
(-100 to 260) °C	0.11 °C		
Capacitance – Measure ¹	(1 to 5) nF	0.1 nF	Comparison to Fluke 87 Digital Multimeter
	(5 to 50) nF	1 nF	
	(50 to 500) nF	10 nF	
	500 nF to 5 μF	0.15 nF	
Capacitance – Measure ¹ (1 kHz)	100 pF to 1μF	5.65 pF/nF + 1.2 nF	Comparison to B&K Precision 885 LCR/ESR Meter
Capacitance – Measure ¹ (50, 60) Hz	Up to 2 nF	0.094 % of reading + 1.2 pF	Comparison to Fluke 8588A Reference Multimeter
	(1.8 to 20) nF	0.075 % of reading + 1.8 pF	
	(18 to 200) nF	0.044 % of reading + 10 pF	
	(0.18 to 2) μF	0.02 % of reading + 60 pF	
	(1.8 to 20) μF	0.045 % of reading + 1.2 nF	
	(18 to 200) μF	0.049 % of reading + 2.6 nF	
	(0.18 to 2) mF	0.064 % of reading + 0.11 μF	
	(1.8 to 20) mF	0.074 % of reading + 1.1 μF	
(18 to 200) mF	0.07 % of reading + 1.1 μF		
Capacitance – Source ^{1,2} (Synthesized)	Up to 1.2 nF	0.09 % of reading + 2 pF	Comparison to Fluke 5560A Multiproduct Calibrator
	(1.2 to 12) nF	0.09 % of reading + 4 pF	
	(12 to 120) nF	0.1 % of reading + 24 pF	
	(0.12 to 1.2) μF	0.1 % of reading + 0.23 nF	
	(1.2 to 12) μF	0.1 % of reading + 2.3 nF	
	(12 to 120) μF	0.12 % of reading + 19.4 nF	
	(0.12 to 1.2) mF	0.2 % of reading + 0.19 μF	
	(1.2 to 12) mF	0.2 % of reading + 2.3 μF	
(12 to 120) mF	0.39 % of reading + 23.3 μF		

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Inductance – Source ¹ (Variable Artifact)	(1 to 10) mH (10 to 100) mH 100 mH to 1 H (1 to 10) H	23 μH/mH 12 μH/mH 8.7 μH/mH 9 mH/H	Comparison to Decade Inductor
Inductance – Source ^{1,2} (Artifacts)	1 kHz Up to 120 μH (0.12 to 1.2) mH 110 Hz (1.2 to 12) mH 100 Hz (12 to 120) mH 10 Hz (0.12 to 1.2) H 3 Hz (1.2 to 12) H 2 Hz (12 to 120) H	0.16 % of reading + 0.16 μH 0.09 % of reading + 0.78 μH 0.09 % of reading + 7.8 μH 0.09 % of reading + 78 μH 0.12 % of reading + 0.78 mH 0.16 % of reading + 7.8 mH 0.19 % of reading + 78 mH	Comparison to Fluke 5560A Multiproduct Calibrator
Inductance – Measure (1 kHz)	100 μH to 1 H	2.7 μH/mH + 1.2 mH	Comparison to B&K Precision 885 LCR/ESR Meter
DC Voltage – Source ¹	(0 to 220) mV (0.22 to 2.2) V (2.2 to 11) V (11 to 22) V (22 to 220) V (220 to 1 100) V	7.5 nV/mV + 0.4 μV 5.5 μV/V + 0.7 μV 3.6 μV/V + 2.5 μV 3.6 μV/V + 4 μV 5.6 μV/V + 40 μV 7.7 μV/V + 0.4 mV	Comparison to Fluke 5730A Multiproduct Calibrator
DC Voltage – Source ^{1,2}	(0 to 120) mV (0.12 to 1.2) V (1.2 to 12) V (12 to 120) V (120 to 1 020) V	9.5 nV/mV + 0.62 μV 6.5 μV/V + 0.78 μV 6.3 μV/V + 7.8 μV 8.8 μV/V + 78 μV 8.7 μV/V + 0.78 mV	Comparison to Fluke 5560A Multiproduct Calibrator
DC Voltage – Measure ¹	(0 to 100) mV (0.1 to 1) V (1 to 10) V (10 to 100) V (100 to 1 000) V	8 μV/V + 0.21 μV 3 μV/V + 0.4 μV 3 μV/V + 0.7 μV 4.4 μV/V + 29 μV 4.7 μV/V + 0.48 mV	Comparison to Fluke 8588A Reference Multimeter
DC High Voltage – Measure ¹	100 V to 10 kV (10 to 35) kV (35 to 90) kV	0.036 % of reading + 40 mV 0.041 % of reading + 0.91 V 0.064 % of reading + 1 V	Comparison to Vitretek 4700 Precision High Voltage Meter



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source ¹	(0.22 to 2.2) mV		Comparison to Fluke 5730A Multiproduct Calibrator
	(10 to 20) Hz	0.8 μV/mV + 4 μV	
	(20 to 40) Hz	0.8 μV/mV + 4 μV	
	40 Hz to 20 kHz	0.75 μV/mV + 4 μV	
	(20 to 50) kHz	0.8 μV/mV + 4 μV	
	(50 to 100) kHz	1 μV/mV + 5 μV	
	(100 to 300) kHz	0.7 μV/mV + 10 μV	
	(300 to 500) kHz	3.1 μV/mV + 20 μV	
	500 kHz to 1 MHz	4.3 μV/mV + 20 μV	
	(2.2 to 22) mV		
	(10 to 20) Hz	0.29 μV/mV + 4 μV	
	(20 to 40) Hz	0.13 nV/mV + 4 μV	
	40 Hz to 20 kHz	0.12 nV/mV + 4 μV	
	(20 to 50) kHz	0.25 μV/mV + 4 μV	
	(50 to 100) kHz	0.6 μV/mV + 5 μV	
	(100 to 300) kHz	1.2 μV/mV + 10 μV	
	(300 to 500) kHz	1.7 μV/mV + 20 μV	
	500 kHz to 1 MHz	3.3 μV/mV + 20 μV	
	(22 to 220) mV		
	(10 to 20) Hz	0.75 μV/mV + 7 μV	
	(20 to 40) Hz	0.11 μV/mV + 7 μV	
	40 Hz to 20 kHz	0.07 μV/mV + 7 μV	
	(20 to 50) kHz	0.14 μV/mV + 7 μV	
	(50 to 100) kHz	0.36 μV/mV + 17 μV	
	(100 to 300) kHz	0.75 μV/mV + 20 μV	
	(300 to 500) kHz	1.5 μV/mV + 25 μV	
	500 kHz to 1 MHz	3.3 μV/mV + 45 μV	
	(0.22 to 2.2) V		
(10 to 20) Hz	0.12 mV/V + 15 μV		
(20 to 40) Hz	0.11 mV/V + 15 μV		
40 Hz to 20 kHz	61 μV/V + 8 μV		
(20 to 50) kHz	88 μV/V + 10 μV		
(50 to 100) kHz	0.14 mV/V + 30 μV		
(100 to 300) kHz	0.55 mV/V + 80 μV		
(300 to 500) kHz	2.5 mV/V + 0.2 mV		
500 kHz to 1 MHz	3.2 mV/V + 0.3 mV		



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source ¹	(2.2 to 22) V		Comparison to Fluke 5730A Multiproduct Calibrator
	(10 to 20) Hz	0.28 mV/V + 0.4 mV	
	(20 to 40) Hz	0.11 mV /V + 0.15 mV	
	40 Hz to 20 kHz	57 μV/V + 50 μV	
	(20 to 50) kHz	84 μV/V + 0.1 mV	
	(50 to 100) kHz	0.54 mV/V + 0.2 mV	
	(100 to 300) kHz	0.62 mV/V + 0.6 mV	
	(300 to 500) kHz	2.4 mV/V + 2 mV	
	500 kHz to 1 MHz	3.2 mV/V + 3.2 mV	
	(22 to 220) V		
	(10 to 20) Hz	0.28 mV/V + 4 mV	
	(20 to 40) Hz	0.11 mV/V = 1.5 mV	
	40 Hz to 20 kHz	82 μV/V + 0.6 mV	
	(20 to 50) kHz	0.3 mV/V + 1 mV	
(50 to 100) kHz	0.19 mV/V + 2.5 mV		
AC Voltage – Source ^{1,2}	(220 to 1 100) V		Comparison to Fluke 5560A Multiproduct Calibrator
	(15 to 50) Hz	0.38 mV/V + 16 mV	
	50 Hz to 1 kHz	0.13 mV/V + 3.5 mV	
	(1 to 12) mV		
	(3 to 5) Hz	2 μV/mV + 6 μV	
	(5 to 10) Hz	0.7 μV/mV + 6 μV	
	10 Hz to 20 kHz	0.13 μV/mV + 5 μV	
	(20 to 50) kHz	0.3 μV/mV + 5 μV	
	(50 to 100) kHz	1.3 μV/mV + 12 μV	
	(100 to 300) kHz	6.3 μV/mV + 24 μV	
	(300 to 500) kHz	6.3 μV/mV + 24 μV	
	(12 to 120) mV		
	(3 to 5) Hz	2 μV/V + 6 μV	
	(5 to 10) Hz	0.73 μV/mV + 6 μV	
10 Hz to 20 kHz	0.12 μV/V + 5 μV		
(20 to 50) kHz	0.27 μV/V + 7 μV		
(50 to 100) kHz	0.64 μV/V + 16 μV		
(100 to 300) kHz	1.6 μV/V + 24 μV		
(300 to 500) kHz	1.6 μV/mV + 24 μV		



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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source ^{1,2}	(0.12 to 1.2) V		Comparison to Fluke 5560A Multiproduct Calibrator
	(3 to 5) Hz	2.1 mV/V + 59 μV	
	(5 to 10) Hz	0.71 mV/V + 55 μV	
	(10 to 40) Hz	0.12 mV/V + 47 μV	
	40.01 Hz to 20 kHz	0.12 mV/V + 6.2 μV	
	(20 to 50) kHz	0.24 mV/V + 11 μV	
	(50 to 100) kHz	0.55 mV/V + 31 μV	
	(100 to 300) kHz	1.6 mV/V + 63 μV	
	(300 to 500) kHz	1.5 mV/V + 63 μV	
	(1.2 to 12) V		
	(3 to 5) Hz	2 mV/V + 0.6 mV	
	(5 to 10) Hz	0.7 mV/V + 0.6 mV	
	(10 to 40) Hz	0.12 mV/V + 0.3 mV	
	40.01 Hz to 20 kHz	0.12 mV/V + 40 μV	
	(20 to 50) kHz	0.24 mV/V + 40 μV	
	(50 to 100) kHz	0.56 mV/V + 0.1 mV	
	(100 to 300) kHz	1.7 mV/V + 0.5 mV	
	(300 to 500) kHz	1.7 mV/V + 0.5 mV	
	(12 to 120) V		
	(3 to 5) Hz	2 mV/V + 5.9 mV	
	(5 to 10) Hz	0.7 mV/V + 5.9 mV	
	(10 to 40) Hz	0.12 mV/V + 2.8 mV	
	40.01 Hz to 20 kHz	0.12 mV/V + 0.4 mV	
	(20 to 50) kHz	0.24 mV/V + 0.4 mV	
(50 to 100) kHz	0.57 mV/V + 1 mV		
(120 to 300) V			
(3 to 5) Hz	2 mV/V + 59 mV		
(5 to 10) Hz	0.7 mV/V + 59 mV		
10 Hz to 20 kHz	0.12 mV/V + 6.2 mV		
(20 to 50) kHz	0.24 mV/V + 6.2 mV		
(50 to 100) kHz	1.3 mV/V + 9.7 mV		
(300 to 1 020) V			
(3 to 5) Hz	2 mV/V + 59 mV		
(5 to 10) Hz	0.7 mV/V + 59 mV		
10 Hz to 10 kHz	0.12 mV/V + 63 mV		



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Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure ¹	Up to 2.2 mV		Comparison to Fluke 5790A AC Measurement Standard
	(10 to 20) Hz	1.3 mV/V + 1 μV	
	(20 to 40) Hz	0.6 mV/V + 1 μV	
	40 Hz to 20 kHz	0.38 mV/V + 1 μV	
	(20 to 50) kHz	0.66 mV/V + 1.6 μV	
	(50 to 100) kHz	0.94 mV/V + 1.9 μV	
	(100 to 300) kHz	1.8 mV/V + 3.1 μV	
	(300 to 500) kHz	2 mV/V + 6.2 μV	
	500 kHz to 1 MHz	4 mV/V + 6.2 μV	
	(2.2 to 7) mV		
	(10 to 20) Hz	0.66 mV/V + 1 μV	
	(20 to 40) Hz	0.31 mV/V + 1 μV	
	40 Hz to 20 kHz	0.19 mV/V + 1 μV	
	(20 to 50) kHz	0.33 mV/V + 1.6 μV	
	(50 to 100) kHz	0.48 mV/V + 1.9 μV	
	(100 to 300) kHz	0.97 mV/V + 3.1 μV	
	(300 to 500) kHz	1.1 mV/V + 6.2 μV	
	500 kHz to 1 MHz	2.8 mV/V + 6.2 μV	
	(7 to 22) mV		
	(10 to 20) Hz	0.9 mV/V + 1 μV	
	(20 to 40) Hz	0.38 mV/V + 1 μV	
	40 Hz to 20 kHz	0.22 mV/V + 1 μV	
	(20 to 50) kHz	0.21 mV/V + 1.6 μV	
	(50 to 100) kHz	0.28 mV/V + 1.9 μV	
	(100 to 300) kHz	0.73 mV/V + 3.1 μV	
	(300 to 500) kHz	0.85 mV/V + 6.2 μV	
	500 kHz to 1 MHz	2.1 mV/V + 6.2 μV	
	(22 to 70) mV		
(10 to 20) Hz	0.47 mV/V + 1.2 μV		
(20 to 40) Hz	0.45 mV/V + 1.2 μV		
40 Hz to 20 kHz	0.28 mV/V + 1.2 μV		
(20 to 50) kHz	0.18 mV/V + 1.6 μV		
(50 to 100) kHz	0.26 mV/V + 1.9 μV		
(100 to 300) kHz	0.56 mV/V + 3.1 μV		
(300 to 500) kHz	0.77 mV/V + 6.2 μV		
500 kHz to 1 MHz	1.1 mV/V + 6.2 μV		



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure ¹	(70 to 220) mV		Comparison to Fluke 5790A AC Measurement Standard
	(10 to 20) Hz	0.96 mV/V + 1.2 μV	
	(20 to 40) Hz	0.59 mV/V + 1.2 μV	
	40 Hz to 20 kHz	0.26 mV/V + 1.2 μV	
	(20 to 50) kHz	0.31 mV/V + 1.6 μV	
	(50 to 100) kHz	0.44 mV/V + 1.9 μV	
	(100 to 300) kHz	0.59 mV/V + 3.1 μV	
	(300 to 500) kHz	1.1 mV/V + 6.2 μV	
	500 kHz to 1 MHz	1.9 mV/V + 6.2 μV	
	(220 to 700) mV		
	(10 to 20) Hz	2.4 mV/V + 1.2 μV	
	(20 to 40) Hz	2.2 mV/V + 1.2 μV	
	40 Hz to 20 kHz	1.1 mV/V + 1.2 μV	
	(20 to 50) kHz	1.5 mV/V + 1.6 μV	
	(50 to 100) kHz	0.82 mV/V + 1.9 μV	
	(100 to 300) kHz	2.4 mV/V + 3.1 μV	
	(300 to 500) kHz	1.2 mV/V + 6.2 μV	
	500 kHz to 1 MHz	1.9 mV/V + 6.2 μV	
	(0.7 to 2.2) V		
	(10 to 20) Hz	0.15 mV/V	
	(20 to 40) Hz	53 μV/V	
	40 Hz to 20 kHz	23 μV/V	
	(20 to 50) kHz	40 μV/V	
	(50 to 100) kHz	60 μV/V	
	(100 to 300) kHz	0.15 mV/V	
	(300 to 500) kHz	0.24 mV/V	
	500 kHz to 1 MHz	0.94 mV/V	
	(2.2 to 7) V		
(10 to 20) Hz	60 μV/V		
(20 to 40) Hz	55 μV/V		
40 Hz to 20 kHz	26 μV/V		
(20 to 50) kHz	42 μV/V		
(50 to 100) kHz	69 μV/V		
(100 to 300) kHz	0.17 mV/V		
(300 to 500) kHz	0.36 mV/V		
500 kHz to 1 MHz	1.2 mV/V		

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure ¹	(7 to 22) V		Comparison to Fluke 5790A AC Measurement Standard
	(10 to 20) Hz	0.29 mV/V	
	(20 to 40) Hz	65 μ V/V	
	40 Hz to 20 kHz	45 μ V/V	
	(20 to 50) kHz	44 μ V/V	
	(50 to 100) kHz	68 μ V/V	
	(100 to 300) kHz	0.17 mV/V	
	(300 to 500) kHz	0.36 mV/V	
	500 kHz to 1 MHz	1.2 mV/V	
	(22 to 70) V		
	(10 to 20) Hz	0.64 mV/V	
	(20 to 40) Hz	0.27 mV/V	
	40 Hz to 20 kHz	62 μ V/V	
	(20 to 50) kHz	0.14 mV/V	
	(50 to 100) kHz	0.19 mV/V	
	(100 to 300) kHz	0.45 mV/V	
	(300 to 500) kHz	0.5 mV/V	
	500 kHz to 1 MHz	1.2 mV/V	
	(70 to 220) V		
	(10 to 20) Hz	3.3 mV/V	
	(20 to 40) Hz	0.2 mV/V	
	40 Hz to 20 kHz	0.15 mV/V	
	(20 to 50) kHz	0.23 mV/V	
	(50 to 100) kHz	0.39 mV/V	
	(100 to 300) kHz	0.31 mV/V	
	(300 to 500) kHz	0.56 mV/V	
	(220 to 700) V		
	(10 to 20) Hz	0.95 mV/V	
(20 to 40) Hz	0.79 mV/V		
40 Hz to 20 kHz	0.9 mV/V		
(20 to 50) kHz	6.1 mV/V		
(50 to 100) kHz	6.6 mV/V		
(700 to 1 000) V			
(10 to 20) Hz	0.32 mV/V		
(20 to 40) Hz	1.1 mV/V		
40 Hz to 20 kHz	1.3 mV/V		
(20 to 50) kHz	1.5 mV/V		
(50 to 100) kHz	6.6 mV/V		

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure ¹ (relative to 1 kHz)	Up to 2.2 mV		Comparison to Fluke 5790A AC Measurement Standard with Wideband Option
	500 kHz to 1.2 MHz	0.08 % of reading + 1 μV	
	(1.2 to 2) MHz	0.08 % of reading + 1 μV	
	(2 to 10) MHz	0.16 % of reading + 1 μV	
	(10 to 20) MHz	0.27 % of reading + 1 μV	
	(20 to 30) MHz	0.62 % of reading + 1.6 μV	
	(2.2 to 7) mV		
	500 kHz to 1.2 MHz	0.11 % of reading + 1 μV	
	(1.2 to 2) MHz	0.14 % of reading + 1 μV	
	(2 to 10) MHz	0.16 % of reading + 1 μV	
	(10 to 20) MHz	0.18 % of reading + 1 μV	
	(20 to 30) MHz	0.62 % of reading + 1 μV	
	(7 to 22) mV		
	500 kHz to 1.2 MHz	0.22 % of reading	
	(1.2 to 2) MHz	0.18 % of reading	
	(2 to 10) MHz	0.24 % of reading	
	(10 to 20) MHz	0.52 % of reading	
	(20 to 30) MHz	0.74 % of reading	
	(22 to 70) mV		
	500 kHz to 1.2 MHz	0.22 % of reading	
	(1.2 to 2) MHz	0.23 % of reading	
	(2 to 10) MHz	0.39 % of reading	
	(10 to 20) MHz	0.7 % of reading	
	(20 to 30) MHz	0.7 % of reading	
(70 to 220) mV			
500 kHz to 1.2 MHz	0.32 % of reading		
(1.2 to 2) MHz	0.34 % of reading		
(2 to 10) MHz	0.49 % of reading		
(10 to 20) MHz	0.62 % of reading		
(20 to 30) MHz	0.84 % of reading		
(220 to 700) mV			
500 kHz to 1.2 MHz	0.31 % of reading		
(1.2 to 2) MHz	0.28 % of reading		
(2 to 10) MHz	0.43 % of reading		
(10 to 20) MHz	0.47 % of reading		
(20 to 30) MHz	0.65 % of reading		

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure ¹ (relative to 1 kHz)	(0.7 to 2.2) V		Comparison to Fluke 5790A AC Measurement Standard with Wideband Option
	500 kHz to 1.2 MHz	0.07 % of reading	
	(1.2 to 2) MHz	0.13 % of reading	
	(2 to 10) MHz	0.2 % of reading	
	(10 to 20) MHz	0.25 % of reading	
	(20 to 30) MHz	0.42 % of reading	
	(2.2 to 7) V		
	500 kHz to 1.2 MHz	0.05 % of reading	
	(1.2 to 2) MHz	0.05 % of reading	
	(2 to 10) MHz	0.11 % of reading	
(10 to 20) MHz	0.16 % of reading		
(20 to 30) MHz	0.36 % of reading		
AC High Voltage – Measure ¹	60 Hz		Comparison to Vitretek 4700 Precision High Voltage Meter
	10 V to 10 kV	0.14 % of reading + 0.12 V	
	(10 to 35) kV	0.12 % of reading + 0.84 V	
	(35 to 70) kV	0.14 % of reading + 1.4 V	
Phase – Measure ¹	Up to 360 °		Comparison to Clarke-Hess 6000A Precision Phase Meter
	5 Hz to 2 kHz	0.026 °	
	(2 to 5) kHz	0.037 °	
	(5 to 10) kHz	0.051 °	
	(10 to 50) kHz	0.062 °	
	50 kHz to 1 MHz	0.24 °	
Phase – Source ^{1,2}	(0 to 360) °		Comparison to Fluke 5560A Multiproduct Calibrator
	(3 to 65) Hz	0.1 °	
	(1 to 360) °		
	(65 to 500) Hz	0.2 °	
	(2 to 360) °		
	500 Hz to 1 kHz	0.4 °	
	(3 to 360) °		
	(1 to 5) kHz	1.9 °	
	(4 to 360) °		
	(5 to 10) kHz	3.9 °	
(5 to 360) °			
(10 to 30) kHz	7.8 °		



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of Thermocouple Indicators – Source/Measure ¹	Type B		Comparison to Fluke 7526A Precision Process Calibrator
	(600 to 800) °C	0.36 °C	
	(800 to 1 550) °C	0.29 °C	
	(1 550 to 1 820) °C	0.22 °C	
	Type C		
	(0 to 1 000) °C	0.16 °C	
	(1 000 to 1 800) °C	0.23 °C	
	(1 800 to 2 000) °C	0.27 °C	
	(2 000 to 2 316) °C	0.36 °C	
	Type E		
	(-250 to -200) °C	0.26 °C	
	(-200 to -100) °C	0.12 °C	
	(-100 to 0) °C	0.09 °C	
	(0 to 600) °C	0.08 °C	
	(600 to 1 000) °C	0.1 °C	
	Type J		
	(-210 to -100) °C	0.14 °C	
	(-100 to 800) °C	0.09 °C	
	(800 to 1 200) °C	0.1 °C	
	Type K		
	(-250 to -200) °C	0.47 °C	
(-200 to -100) °C	0.16 °C		
(-100 to 800) °C	0.1 °C		
(800 to 1 372) °C	0.13 °C		
Type L			
(-200 to 0) °C	0.1 °C		
(0 to 900) °C	0.09 °C		
Type N			
(-250 to -200) °C	0.74 °C		
(-200 to -100) °C	0.23 °C		
(-100 to 0) °C	0.12 °C		
(0 to 100) °C	0.11 °C		
(100 to 800) °C	0.1 °C		
(800 to 1 300) °C	0.12 °C		



ANSI National Accreditation Board

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of Thermocouple Indicators – Source/Measure ¹	Type R		Comparison to Fluke 7526A Precision Process Calibrator
	(-50 to -25) °C	0.56 °C	
	(-25 to 0) °C	0.46 °C	
	(0 to 100) °C	0.4 °C	
	(100 to 400) °C	0.29 °C	
	(400 to 600) °C	0.22 °C	
	(600 to 1 000) °C	0.21 °C	
	(1 000 to 1 600) °C	0.19 °C	
	(1 600 to 1 767) °C	0.23 °C	
	Type S		
	(-50 to -25) °C	0.52 °C	
	(-25 to 0) °C	0.44 °C	
	(0 to 100) °C	0.39 °C	
	(100 to 400) °C	0.3 °C	
	(400 to 600) °C	0.23 °C	
(600 to 1 000) °C	0.22 °C		
(1 000 to 1 600) °C	0.22 °C		
(1 600 to 1 767) °C	0.27 °C		
Type T			
(-250 to -200) °C	0.36 °C		
(-200 to -100) °C	0.16 °C		
(-100 to 0) °C	0.11 °C		
(0 to 200) °C	0.09 °C		
(200 to 400) °C	0.09 °C		
Oscilloscopes ¹			Comparison to Fluke 5500A w/SC300 Multiproduct Calibrator
Amplitude			
50 Ω Load	1.8 mVp-p to 2.2 Vp-p	2.3 mV/V + 0.81 mV	
1 MΩ Load	1.8 mVp-p to 105 Vp-p	2.7 mV/V + 81 μV	
Bandwidth (relative to 50 kHz)			
50 Ω load	50 kHz to 100 MHz	5.2 % of reading + 0.38 V	
	(100 to 300) MHz	5.9 % of reading + 0.37 V	
Risetime			
50 Ω load	Nominal: (250 to 350) ps	100 ps	
Gauss Meters / Hall Effect Meters	(-5 to 5) Gs	0.1 Gs	Comparison to Helmholtz Coil, Power Supply
	(-10 to 10) Gs	0.2 Gs	
	(-20 to 20) Gs	0.4 Gs	
	(-50 to 50) Gs	1 Gs	
	(-100 to 100) Gs	2 Gs	

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
RF Absolute Power – Measure ^{1,3}	(-23 to +10) dBm 100 MHz ≤ f < 6 GHz 6 GHz ≤ f ≤ 18 GHz (> 10 to 20) dBm 100 MHz ≤ f < 500 MHz 500 MHz ≤ f < 1.2 GHz 1.2 GHz ≤ f < 6 GHz 6 GHz ≤ f ≤ 18 GHz (-30 to -10) dBm 100 kHz ≤ f < 10 MHz 10 MHz ≤ f < 1.2 GHz 1.2 GHz ≤ f ≤ 4.2 GHz (> -10 to +20) dBm 100 kHz ≤ f < 10 MHz 10 MHz ≤ f < 1.2 GHz 1.2 GHz ≤ f ≤ 4.2 GHz	0.08 dB 0.16 dB 0.18 dB 0.17 dB 0.18 dB 0.19 dB 0.1 dB 0.18 dB 0.11 dB 0.17 dB 0.17 dB 0.17 dB	Comparison to Agilent E4418B RF Power Meter, Agilent 8481A Power Sensor
Distortion – Measure ¹	(-80 to 0) dB 20 Hz to 20 kHz (20 to 100) kHz	1.2 dB 2.3 dB	Comparison to Agilent 8903B Audio Analyzer
Absolute Power – Source ^{1,3} into 50 Ω	(0.05 to 10) V _{p-p} Up to 100 kHz 100 kHz to 1 MHz (1 to 15) MHz	60 mV 75 mV 92 mV	Comparison to Agilent 33120A Arbitrary Function Generator
Absolute Power – Measure ¹ (-120 to 20) dBm	(-120 to 20) dBm 10 MHz to 1.3 GHz	1 dB	Comparison to Rigol DSA1030A-TG Spectrum Analyzer
Tuned RF Power – Measure ¹ 2.5 MHz to 1.3 GHz	(-115 to 0) dBm (-127 to -115) dBm	2 dB 1.3 dB	Comparison to Agilent 8902A Modulation Analyzer, Agilent 11722A Power Sensor
Frequency Modulation – Measure ¹			
Freq: 250 kHz to 10 MHz	Deviation: ≤ 40 kHz Rate: 20 Hz to 10 kHz	0.41 kHz	Comparison to Agilent 8902A Modulation Analyzer
Freq: 10 MHz to 1.3 GHz	Deviation: ≤ 40 kHz Rate: 20 Hz to 100 kHz	1.5 kHz	
Freq: 10 MHz to 1.3 GHz	Deviation: ≤ 40 kHz Rate: 20 Hz to 200 kHz	5.9 kHz	



ANSI National Accreditation Board

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Amplitude Modulation – Measure ¹ Freq: 150 kHz to 10 MHz	Depth: (5 to 99) % Rate: 50 Hz to 10 kHz	2.5 % Depth	Comparison to Agilent 8902A Modulation Analyzer
	Depth: (5 to 99) % Rate: 20 Hz to 10 kHz	3.7 % Depth	
Freq: 10 MHz to 1.3 GHz	Depth: (5 to 99) % Rate: 50 Hz to 50 kHz	1.5 % Depth	
	Depth: (5 to 99) % Rate: 20 Hz to 100 kHz	3.7 % Depth	
Attenuation – Source Coaxial, Fixed ¹ 3 dB	DC to 8 GHz, SWR < 1.25:1 (8 to 12.4) GHz, SWR < 1.3:1	0.35 dB 0.35 dB	Comparison to Agilent 8491A Coaxial Fixed Attenuator with Type-N
Attenuation – Source Coaxial, Fixed ¹ 6 dB	DC to 8 GHz, SWR < 1.2:1 (8 to 12.4) GHz, SWR < 1.3:1	0.47 dB 0.47 dB	Comparison to Agilent 8491A Coaxial Fixed Attenuator with Type-N
10 dB	DC to 8 GHz, SWR < 1.2:1 (8 to 12.4) GHz, SWR < 1.3:1	0.7 dB 0.7 dB	
20 dB	DC to 8 GHz, SWR < 1.2:1 (8 to 12.4) GHz, SWR < 1.3:1	0.7 dB 0.7 dB	
	DC to 8 GHz, SWR < 1.2:1 (8 to 12.4) GHz, SWR < 1.3:1	0.7 dB 0.7 dB	



ANSI National Accreditation Board

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Attenuation – Source Coaxial, Fixed ¹ 30 dB 60 dB	DC to 8 GHz, SWR < 1.2:1 (8 to 12.5) GHz, SWR < 1.3:1 DC to 8 GHz, SWR < 1.2:1 (8 to 12.5) GHz, SWR < 1.3:1	1.2 dB 1.2 dB 2.3 dB 2.3 dB	Comparison to Agilent 8491A Coaxial Fixed Attenuator with Type-N
Thermal Noise Figure System – Measure ¹ (0 to 30 dB)	10 MHz to 1.5 GHz SWR 1.7:1 ENR (14 to 16) dB	0.3 dB	Comparison to Agilent 8970A Noise Figure Meter, Agilent 346B Noise Source
Thermal Noise Figure System – Generate ¹ ENR (14 to 16) dB	10 MHz to 18 GHz SWR 1.25:1	0.003 2 dB/GHz + 0.27 dB	Comparison to Agilent 346B Noise Source

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Inside Micrometers ^{1,5} (0.001 in Resolution)	Up to 4 in (4 to 20) in (20 to 36) in (36 to 60) in	580 μin (560 + 2.1L) μin (500 + 4.6L) μin (400 + 6.7L) μin	Comparison to Gage Blocks
Feeler Gages	Up to 0.25 in Up to 6 mm	20 μin 0.51 μm	Comparison to Gages Blocks, Universal Length Measuring Machine
Surveillance Micrometer Masters ⁵	(1 to 12) in (25 to 300) mm	(5.5 + 11L) μin (0.14 + 0.011L) μm	Comparison to Gages Blocks, Universal Length Measuring Machine

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Taper Thread Plugs Pitch Diameter	Up to 3 in	130 μin	Comparisons to Thread Measuring Wires, Taper Block, Universal Length Measuring Machine
Major Diameter	Up to 3 in	100 μin	Taper Block, Universal Length Measuring Machine
Length at Notch	Up to 3 in	250 μin	Gage Blocks, Height Gage
Radius Gage	(0 to 0.5) in	260 μin	Comparison to Vision System
Rulers	Up to 24 in	0.005 8 in	Comparison to Vision System
Steel Tape ¹	Up to 10 m	250 μm	Comparison to Master Tape
Vision System X-Y Linearity	Up to 18 in	100 μin	Comparisons to Master Grid,
Z Linearity	Up to 4 in	52 μin	Gage Blocks
Levels ¹ Base Flatness Parallelism	Up to 12 in	100 μin	Comparison to Height Transfer Standard, Gage Blocks, Surface Plate
Metal / X-Ray Detector Standards ^{4,5}	(0.031 5 to 0.28) in	(5.5 + 11L) μin	Comparison to Universal Length Measuring Machine
Gage Blocks ⁵	(0.01 to 5) in	(7 + 1.3L) μin	Comparison to Gage Block Comparator, Master Gage Blocks
Gage Blocks ⁵	(5 to 12) in	(2.3 + 2.4L) μin	Comparison to P&W LMU 175 Labmaster [®] Universal, Master Gage Blocks
Laser Micrometer ¹ (1 μin Resolution)	(0.01 to 2) in	23 μin	Comparison to XXX Pin Gages
Angle Blocks ⁴	(1 to 45)°	0.2 "/° + 14"	Comparison to Sine Block, Height Transfer Standard, Surface Plate

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Bench / Super Micrometers / Universal Length Measuring Machine ⁵			
Linearity	Up to 4 in	$(3 + 22L) \mu\text{in}$	Comparisons to Gage Blocks
Anvil Parallelism	25 μin TIR	4 μin	Optical Flats w/ Monochromatic Light
Force	2 ozf 4 ozf 8 ozf 16 ozf 40 ozf	0.019 ozf 0.021 ozf 0.027 ozf 0.74 ozf 0.78 ozf	Digital Force Gage
Snap Gages ¹	(0.05 to 4) in	22 μin	Comparison to Gage Blocks
Pin Gages / Cylindrical Plug Gages	(0.01 to 2) in	46 μin	Comparison to Laser Micrometer
Pin Gages / Cylindrical Plug Gages ⁵	Up to 2 in (1.9 to 18) in	$(6.9 + 10D) \mu\text{in}$ $(4.7 + 11D) \mu\text{in}$	Comparison to Universal Length Measuring Machine
Cylindrical Rings ⁵	(0.275 to 13.25) in	$(41 + 11D) \mu\text{in}$	Comparison to Master Rings, Universal Length Measuring Machine
Thread Wires ⁵	Up to 0.144 34 in	$(11 + 1.3D) \mu\text{in}$	Comparison to Universal Length Measuring Machine
Measuring Rods ⁵	(1 to 12) in (12 to 18) in (18 to 59) in	$(5.5 + 11L) \mu\text{in}$ $(1.7 + 12L) \mu\text{in}$ $(91 + 13L) \mu\text{in}$	Comparison to Gage Blocks, Universal Length Measuring Machine
Height Masters ⁵			
Micrometer Linearity	Up to 1 in	66 μin	Comparison to Height Transfer Standard, Gage Blocks, Surface Plate
Step Height, Top/Bottom	(1 to 24) in	$(43 + 2L) \mu\text{in}$	
Step Parallelism	Up to 100 μin	84 μin	
Thread Plugs ⁵			
Pitch Diameter (5 to 100) TPI	Up to 8 in	$(76 + 7.7D) \mu\text{in}$	Comparison to Thread Wires, Universal Length Measuring Machine

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Thread Rings ¹	Up to 2 in	340 μin	Comparison to Master Thread Plugs
Solid Thread Rings ⁵ (5.5 to 40) TPI (0.7 to 4.5) Pitch	(0.125 to 4) in	(23 + 6.8L) μin	Comparison to P&W LMU 175 Labmaster® Universal. Class XX Master Ring Gage
External Spline Gages ⁵ Measurement over Pins	Up to 8 in	(180 + 30D) μin	Comparisons to Gear Wires, Universal Length Measuring Machine
Circular Tooth Thickness	Up to 8 in	(120 + 20L) μin	Vision System
Major Diameter	Up to 8 in	(30 + 16D) μin	Universal Length Measuring Machine
Chamfer Gages / Countersink Gages ¹	Up to 3 in	540 μin	Comparison to Master Cylindrical Rings
Bore Gages ¹ (0.000 1 in Resolution)	(0.25 to 6) in (1 to 8) in	190 μin 0.002 % of reading + 1 800 μin	Comparison to Master Cylindrical Rings, Bore Gage Calibrator
Calipers ^{1,5} (0.000 5 in Resolution) (0.001 in Resolution)	(0.05 to 24) in (0.05 to 12) in (12 to 80) in	470 μin 800 μin (600 + 19L) μin	Comparison to Gage Blocks, End Measuring Rod, Surface Plate
Outside Micrometers ^{1,5} 50 μin Resolution 100 μin Resolution 100 μin Resolution 0.001 in Resolution	Up to 1 in Up to 1 in (1 to 12) in (12 to 20) in	(35 + 8.8L) μin (66 + 19L) μin (770 + 26L) μin (1 600 + 106L) μin	Comparison to Gage Blocks, End Measuring Rods, Surface Plate
Depth Micrometers ^{1,5} (0.000 1 in Resolution) (0.001 in Resolution)	Up to 12 in Up to 12 in	(88 + 4L) μin (890 + 23L) μin	Comparison to Gage Blocks, Surface Plate
V-Anvil OD Micrometers ^{1,5} 100 μin Resolution 500 μin Resolution	(0.4 to 1) in (1.25 to 4) in	60 μin (330 + 54L) μin	Comparison to Cylindrical Plug Gages, Pin Gages
Ultrasonic Thickness Gage ^{1,5}	Up to 12 in	(760 + 13L) μin	Comparison to Gage Blocks

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Dial / Digital Indicators ¹ 10 μin resolution 20 μin resolution 50 μin resolution 100 μin resolution 500 μin resolution 0.001 in resolution	(-0.015 to 0.015) in (-0.001 to 0.001) in Up to 2 in Up to 2 in Up to 2 in Up to 2 in	7.3 μin 13 μin 61 μin 110 μin 300 μin 1 200 μin	Comparison to Gage Blocks, Indicator Calibrator, Surface Plate
Test Indicators ¹	50 μin to 0.01 in	61 μin	Comparison to Indicator Calibrator, Surface Plate
Height Gages ^{1,5}	Up to 12 in (12 to 36) in	(35 + 5L) μin (280 + 12L) μin	Comparison to Gage Blocks, Surface Plate, Measuring Rods
Linear Scales ¹	(1 to 142) in	7 μin/in + 0.009 5 μin	Comparison to Measuring Rods
Extensometers ¹ 50 μin resolution	Up to 2 in	140 μin	Comparison to Micrometer Head
Extensometers ¹ 10 μin resolution	Up to 2 in	61 μin	Comparison to Extensometer Calibrator
Optical Comparators ¹ Magnification	10 X to 100 X	210 μin	Comparisons to Glass Scale
Linearity (10 μin Resolution)	Up to 18 in	0.001 5 % of reading + 59 μin	Glass Scale
Angularity	Up to 30°	2'10"	Angle Blocks
Coating Thickness Measuring Systems ¹	Up to 0.018 in	7.7 % of reading	Comparison to Ferrous Coated Thickness Standards
Protractors	Up to 180°	0.06°	Comparison to Height Transfer Standard, Sine Block, Surface Plate
Microscopes ¹	Up to 2 in	160 μin	Comparison to Glass Scale
Profilometers ¹	118 μin 123 μin	3.1 μin 3.1 μin	Comparison to Roughness Standard
Surface Roughness Specimen (Ra)	(10 to 500) μin	3.7 μin	Comparison to Surface Finish Analyzer

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Roundness Measuring System ¹ Radial Error	Up to 5 in	5.5 μin	Comparison to Precision Ball
Coordinate Measuring Machines ⁵ Linear Accuracy	(0.5 to 24.5) in	(88 + 7L) μin	Step Gage, Ball Bars, and ASME B89.4.1 utilized in the calibration of this system parameter.
Volumetric Accuracy	(9 to 25) in	209 μin	
Squareness	(0.25 to 11.75) in	362 μin	
Coordinate Measuring Machines ⁵ Linear Accuracy	(0.5 to 39) in	(20 + 4L) μin	Gage Blocks and ISO 10360-2 utilized in the calibration of this system parameter.
Surface Plates ^{1,5} Overall Flatness	Up to 68 in DL	(5 + 0.5 DL) μin	In accordance with ASME B89.3.7 using Optodyne LDDM Laser Measurement System
Local Area Flatness	Up to 0.03 in	16 μin	Repeat Reading Gage
Optical Flats	Up to 100 μin	5 μin	Comparison to Optical Flat, Monochromatic Light
Inclinometers	Up to 45°	0.06°	Comparison to Sine Plate, Gage Blocks
Crosshead Displacement	(0.2 to 2) in	0.001 5 in/in + 1 800 μin	Dial Depth Indicator and ASTM E2309 utilized in the calibration of this parameter.
Laser Interferometer System (Device for Measuring Displacement w/out Atmospheric Compensation)	Up to 80 in	(0.95 + 0.72L) μin	Master Laser Interferometer per ASME B89.1.8, Back-to-Back Method.
Laser Interferometer System Flatness	Up to 100 μin	5.5 μin	Comparison to Flatness Master
Mahr Dimensionair Gages ¹	(-0.001 5 to 0.001 5) in	59 μin	Comparison to Mahr AMR-12 Magnification Test Kit



ANSI National Accreditation Board

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Aqueous Volumetric Flow Rate ¹ (Inline)	Up to 65 gpm Up to 150 gpm	0.2 % of reading + 0.6 gpm 0.2 % of reading + 0.3 gpm	Comparison to Coriolis Meter
Aqueous Volumetric Flow Rate ¹ (Non-Intrusive)	(100 to 500) gpm (150 to 900) gpm	1.84 % of reading + 0.64 gpm 1.8 % of reading + 0.65 gpm	Comparison to Ultrasonic Transducers
Volumetric Gas Flow Meters, Rotameters	(2 to 20) sccm (10 to 100) sccm (100 to 1 000) sccm (0.5 to 5) slpm (5 to 50) slpm	1 % of reading + 0.6 sccm 1 % of reading + 0.9 sccm 0.81 % of reading + 5.5 sccm 0.14 % of reading + 0.3 slpm 1 % of reading + 0.4 slpm	Comparison to Thermal Volumetric Flow Sensors
Gas Flow Velocity	(50 to 6 000) ft/min	1.3 % of reading + 2 ft/min	Comparison to Master Anemometer, Open Jet Wind Tunnel
Metal Detectors – Magnetic Separation ¹	(0.5 to 6) lbf	0.37 lbf	Comparison to Digital Magnetic Pull Tester
Force Gauges ¹	Up to 21.5 lbf (10 to 110) lbf (50 to 1 050) lbf	0.035 % of reading + 0.000 93 lbf 0.043 % of reading + 0.007 3 lbf 0.051 % of reading + 0.073 lbf	Comparison to NIST Class F Weights, Weight Hanger
Force Machines – Tension ¹	(5 to 50) lbf (76 to 500) lbf (290 to 3 000) lbf (480 to 5 000) lbf (261 to 10 000) lbf (3 000 to 30 000) lbf (3 000 to 60 000) lbf (3 000 to 120 000) lbf (10 000 to 300 000) lbf	0.025 lbf 0.25 lbf 0.61 lbf 2.2 lbf 4.2 lbf 6.5 lbf 12 lbf 0.03 % of reading + 16 lbf 0.02 % of reading + 8 lbf	Load Cell w/ Indicator and ASTM E74 utilized in the calibration of this system.
Force Machines – Compression ¹	(5 to 50) lbf (48 to 500) lbf (88 to 3 000) lbf (450 to 5 000) lbf (1 000 to 10 000) lbf (3 000 to 30 000) lbf (6 000 to 60 000) lbf (60 000 to 120 000) lbf (19 000 to 300 000) lbf (52 000 to 800 000) lbf	0.03 lbf 0.25 lbf 0.61 lbf 2.3 lbf 7.5 lbf 6.4 lbf 17 lbf 0.03 % of reading + 16 lbf 0.02 % of reading + 6 lbf 0.03 % of reading + 10 lbf	Load Cell w/ Indicator and ASTM E74 utilized in the calibration of this system.

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Ductility Tester, Olsen Cup Tester ¹	(300 to 6 000) lbf (6 000 to 30 000) lbf	7.5 lbf 17 lbf	Master Load Cell w/ Indicator and ASTM E74 utilized in the calibration of this system.
Load Cell – Tension ¹	(5 to 50) lbf (76 to 500) lbf (290 to 3 000) lbf (480 to 5 000) lbf (261 to 10 000) lbf (3 000 to 30 000) lbf (3 000 to 60 000) lbf (3 000 to 120 000) lbf (10 000 to 300 000) lbf	0.025 lbf 0.25 lbf 0.61 lbf 2.2 lbf 4.2 lbf 6.5 lbf 12 lbf 0.03 % of reading + 16 lbf 0.02 % of reading + 6 lbf	Master Load Cell w/ Indicator and ASTM E74 utilized in the calibration of this system.
Load Cell – Compression ¹	(5 to 50) lbf (48 to 500) lbf (88 to 3 000) lbf (450 to 5 000) lbf (1 000 to 10 000) lbf (3 000 to 30 000) lbf (6 000 to 60 000) lbf	0.03 lbf 0.25 lbf 0.61 lbf 2.3 lbf 7.5 lbf 6.4 lbf 17 lbf	Master Load Cell w/ Indicator and ASTM E74 utilized in the calibration of this system.
Load Cell – Compression ¹	(60 000 to 120 000) lbf (19 000 to 300 000) lbf (52 000 to 800 000) lbf	0.03 % of reading + 16 lbf 0.02 % of reading + 6 lbf 0.03 % of reading + 10 lbf	Master Load Cell w/ Indicator and ASTM E74 utilized in the calibration of this system.
Rockwell Hardness Testers ¹	HRA Low Middle High HRBW Low Middle High HRC Low Middle High HRE Low High HRF Low High	0.44 HRA 0.38 HRA 0.26 HRA 0.74 HRBW 0.69 HRBW 0.59 HRBW 0.41 HRC 0.36 HRC 0.36 HRC 0.62 HRE 0.55 HRE 0.69 HRF 0.62 HRF	Indirect verification per ASTM E18 using Hardness Blocks

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Rockwell Hardness Testers ¹	HRGw	1.1 HRGw	Indirect verification per ASTM E18 using Hardness Blocks
	Low	0.91 HRGw	
	High		
	HRHw	0.87 HRHw	
	Low	0.45 HRHw	
	High		
	HRLw	0.9 HRLw	
	Low	0.46 HRLw	
	High		
	HRMw	0.69 HRMw	
	Low	0.51 HRMw	
	High		
Superficial Rockwell Hardness Testers ¹	HR15N	0.13 HR15N	Indirect verification per ASTM E18 using Hardness Blocks
		0.16 HR15N	
		0.1 HR15N	
	HR30N	0.67 HR30N	
		0.59 HR30N	
		0.51 HR30N	
	HR45N	0.49 HR45N	
		0.57 HR45N	
		0.5 HR45N	
	HR15TW	0.69 HR15TW	
		0.62 HR15TW	
		0.4 HR15TW	
	HR30TW	0.52 HR30TW	
		0.45 HR30TW	
		0.44 HR30TW	
	HR45TW	0.49 HR45TW	
		0.46 HR45TW	
		0.62 HR45TW	
	HR15Yw	0.83 HR15Yw	
		0.8 HR45Yw	

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Brinell Hardness Testers ¹	(500 to 3 000) kgf	6.7 kgf	Direct verification per ASTM E10, ASTM E74; Class A Proving Ring
Brinell Hardness Testers ¹ Verification	HBW2.5/62.5 Low High HBW2.5/187.5 Low High HBW5/750 Low High HBW10/500 Low High HBW10/1500 Low High HBW10/3000 Low High	2.8 HBW2.5/62.5 6.1 HBW2.5/62.5 2.3 HBW2.5/187.5 16 HBW2.5/187.5 4.9 HBW5/750 16 HBW5/750 0.63 HBW10/500 2.1 HBW10/500 1.2 HBW10/1 500 3.2 HBW10/1 500 3.3 HBW10/3 000 13 HBW10/3 000	Indirect verification per ASTM E10 using Hardness Standards,
Indenter Error	Up to 0.1 mm	57 µm	Stage Micrometer
Brinell Scope ¹	(0 to 7) mm	6.7 µm	Comparison to Stage Micrometer
Vickers Hardness Tester – Force ¹	10 gf 25 gf 50 gf 100 gf 200 gf 300 gf 500 gf 1 kgf 2 kgf 5 kgf 10 kgf 20 kgf 30 kgf 50 kgf	1.1 gf 1.1 gf 1.1 gf 1.1 gf 1.1 gf 2.3 gf 3.4 gf 6.6 gf 13 gf 33 gf 66 gf 0.13 kgf 0.2 kgf 0.33 kgf	Direct verification per ASTM E92 / ISO 6507-2 using Force Gage



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Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Knoop Hardness Tester – Force ¹	10 gf	1.1 gf	Direct verification per ASTM E92 / ISO 6507-2 using Force Gage
	25 gf	1.1 gf	
	50 gf	1.1 gf	
	100 gf	1.1 gf	
	200 gf	1.1 gf	
	300 gf	2.3 gf	
	500 gf	3.4 gf	
	1 kgf	6.1 gf	
	3 kgf	11 gf	
	10 kgf	11 gf	
	15 kgf	11 gf	
	30 kgf	11 gf	
	45 kgf	11 gf	
	60 kgf	33 gf	
	100 kgf	33 gf	
150 kgf	33 gf		
Rockwell Hardness Tester – Force ¹	3 kgf	8 gf	Direct Verification per ASTM E18 using Load Cell w/ Indicator
	10 kgf	24 gf	
	15 kgf	0.21 kgf	
	30 kgf	0.22 kgf	
	45 kgf	0.23 kgf	
	60 kgf	0.25 kgf	
	100 kgf	0.31 kgf	
150 kgf	0.41 kgf		
Rockwell Hardness Testers – Indenter Depth ¹	(0.1 to 200) μm	0.3 μm	Comparison to LVDT Probe w/ Indicator
Rockwell Hardness Testers – Hysteresis ¹ B, E, F, G, H and K Scale	100 Rockwell Units	0.31 HR	Direct Verification using Blunt Indenter and Flat Anvil
	All Other Scales	130 Rockwell Units	

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Vickers Hardness Tester ¹	< 240 HV 0.01	12 HV 0.01	Indirect verification per ASTM E92 / ISO 6507-2 using Hardness Blocks
	> 600 HV 0.01	44 HV 0.01	
	< 240 HV 0.025	11 HV 0.025	
	> 600 HV 0.025	33 HV 0.025	
	< 240 HV 0.05	11 HV 0.05	
	> 600 HV 0.05	30 HV 0.05	
	< 240 HV 0.1	11 HV 0.1	
	> 600 HV 0.1	28 HV 0.1	
	< 240 HV 0.2	9 HV 0.2	
	> 600 HV 0.2	22 HV 0.2	
	< 240 HV 0.3	9 HV 0.3	
	> 600 HV 0.3	21 HV 0.3	
	< 240 HV 0.5	8 HV 0.5	
	> 600 HV 0.5	20 HV 0.5	
	< 240 HV 1	7 HV 1	
	> 600 HV 1	17 HV 1	
	< 240 HV 5	6 HV 5	
	(240 to 600) HV 5	13 HV 5	
	> 600 HV 5	22 HV 5	
	< 240 HV 10	5 HV 10	
(240 to 600) HV 10	10 HV 10		
> 600 HV 10	17 HV 10		
< 240 HV 30	7 HV 30		
(240 to 600) HV 30	11 HV 30		
> 600 HV 30	18 HV 30		
Knoop Hardness Tester ¹	< 250 HK 0.01	9 HK 0.01	Indirect verification per ASTM E92 / ISO 6507-2 using Hardness Blocks
	> 650 HK 0.01	35 HK 0.01	
	< 250 HK 0.025	9 HK 0.025	
	> 650 HK 0.025	24 HK 0.025	
	< 250 HK 0.05	9 HK 0.05	
	> 650 HK 0.05	22 HK 0.05	
	< 250 HK 0.1	9 HK 0.1	
	> 650 HK 0.1	21 HK 0.1	
	< 250 HK 0.2	7 HK 0.2	
	> 650 HK 0.2	17 HK 0.2	
	< 250 HK 0.3	7 HK 0.3	
	> 650 HK 0.3	21 HK 0.3	
	< 250 HK 0.5	7 HK 0.5	
	> 650 HK 0.5	18 HK 0.5	
	< 250 HK 1	8 HK 1	
	> 650 HK 1	18 HK 1	



ANSI National Accreditation Board

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Durometers Spring Force Only Types A, B, O Types D, C, DO	(10 to 90) Duro (10 to 90) Duro	0.7 Duro 0.6 Duro	Partial Direct Verification per ASTM D2240-02B using Durometer Calibrator.
Duro Calibrator Types A, B, O Types D, C, DO	(1.3 to 8.05) N (4.445 to 44.45) N	0.033 N 0.046 % of reading + 0.03 N	Comparison to Digital Force Gage
Pneumatic Pressure Gages ¹	(-0.25 to 0.25) in H ₂ O (-30 to 30) in H ₂ O (20 to 200) in H ₂ O	0.07 % of reading + 0.004 1 inH ₂ O 0.002 9 inH ₂ O 0.72 in H ₂ O	Comparison to Setra & Meriam Calibrator
Pneumatic Pressure Gages	(> 0 to 36) psig (> 0 to 145) psig (> 0 to 500) psig	0.008 5 % of reading + 0.007 2 psi 0.006 5 % of reading + 0.01 psi 0.008 7 % of reading + 0.019 psi	Comparison to Fluke 6270A Pressure Controller with Associated Module
Pneumatic/Hydraulic Pressure Gages ¹	(10 to 2000) psig (100 to 10 000) psig	0.18 % of reading + 0.27 psi 0.075 % of reading + 0.52 psi	Comparison to Deadweight Testers
Pneumatic/Hydraulic Pressure Gages ¹	(0 to 30) psig (0 to 300) psig (0 to 300) psia (0 to 500) psig (0 to 1 000) psig (1 000 to 10 000) psig (5 000 to 50 000) psig (10 000 to 100 000) psig	0.1 % of reading 0.1 % of reading 0.1 % of reading 0.3 psi 0.03 % of reading + 0.54 psi 0.05 % of reading + 17 psi 0.05 % of reading + 58 psi 0.04 % of reading + 380 psi	Comparison to High Accuracy Pressure Gage, Pressure Calibrator
Absolute Pneumatic Pressure Gages	(> 0 to 17.4) psia	0.001 5 % of reading + 0.007 7 psi	Comparison to Fluke 6270A Pressure Controller with Associated Module
Vacuum Gage	(-14.7 to < 0) psi	0.034 % of reading + 0.008 7 psi	Comparison to Fluke 6270A Pressure Controller with Associated Module
Vacuum Gage ¹	(-660 to < 0) mmHg	0.1 % of reading	Comparison to Pressure Calibrator



ANSI National Accreditation Board

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Conventional Mass NIST Class F (Metric)	(1 to 40) g (40 to 100) g (100 to 220) g (0.22 to 3.1) kg 500 g 1 kg 5 kg 10 kg 20 kg	0.000 6 % of reading + 20 µg 0.000 4 % of reading + 0.11 mg 0.000 5 % of reading + 0.17 mg 0.000 13 % of reading + 36 mg 27 mg 27 mg 36 mg 39 mg 0.49 g	Comparison to ASTM E617 Class 1 Weights, Balance
Conventional Mass NIST Class F (Avoirdupois)	0.5 lb 1 lb 2 lb 5 lb 10 lb 20 lb 25 lb 50 lb	26 mg 27 mg 27 mg 14 mg 21 mg 31 mg 37 mg 1.6 g	Comparison to ASTM E617 Class 1 Weights, Balance
Scales and Balances ^{1,6} Metric (SI)	Up to 100 g (100 to 220) g (220 to 320) g (320 to 520) g	0.000 12 % of reading + 29 µg 0.000 12 % of reading + 53 µg 0.000 05 % of reading + 0.21 mg 0.000 06 % of reading + 0.16 mg	ASTM E617 Class 0 weights and NIST Handbook 44 utilized for the calibration of the weighing system.
Scales and Balances ^{1,6} Metric (SI)	Up to 40 g (40 to 100) g (100 to 220) g (220 to 2 100) g (2 100 to 4 200) g (4 200 to 14 200) g (14 200 to 32 000) g	0.000 4 % of reading + 14 µg 0.000 4 % of reading + 16 µg 0.000 5 % of reading + 3.2 µg 0.000 7 % of reading + 3.6 mg 0.000 7 % of reading + 3.1 mg 0.000 3 % of reading + 2.7 mg 0.000 3 % of reading + 30 mg	ASTM E617 Class 1 weights and NIST Handbook 44 utilized for the calibration of the weighing system.
Scales and Balances ^{1,6} Avoirdupois	Up to 10 lb (10 to 50) lb (50 to 250) lb (250 to 500) lb (500 to 1 000) lb	0.008 % of reading + 0.002 lb 0.15 % of reading + 0.001 lb 0.008 % of reading + 0.01 lb 0.006 % of reading + 0.05 lb 0.016 % of reading + 0.18 lb	ASTM E617 Class 3 weights, NIST Class F Weights, and NIST Handbook 44 utilized for the calibration of the weighing system.
Pipettes	(2 to 100) µL (100 to 1 000) µL (1 000 to 10 000) µL	0.37 µL 0.036 % of reading + 0.33 µL 0.005 7 % of reading + 0.61 µL	Gravimetric Method using Analytical Balance

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Moisture Analyzers ^{1,6} Weighing System	Up to 220 g	0.000 4 % of reading + 0.14 mg	ASTM E617 Class 1 weights and NIST Handbook 44 utilized for the calibration of the weighing system.
Temperature	160 °C	2.5 °C	Reference Thermometer
Torque Watch ¹	(0.5 to 2.5) ozf·in (2 to 10) ozf·in (6 to 43) ozf·in (30 to 215) ozf·in	0.3 % of reading + 0.08 ozf·in 0.2 % of reading + 0.07 ozf·in 0.2 % of reading + 0.3 ozf·in 0.2 % of reading + 3 ozf·in	Comparison to Torque Watch Calibrator
Torque Devices ¹	(2.5 to 25) lbf·in (25 to 250) lbf·in (100 to 1 000) lbf·in (25 to 250) lbf·ft (80 to 800) lbf·ft (100 to 1 000) lbf·ft (500 to 5 000) lbf·ft	0.54 % of reading + 0.05 lbf·in 0.64 % of reading + 0.02 lbf·in 0.76 % of reading + 0.24 lbf·in 1.2 % of reading + 0.05 lbf·in 2 lbf·ft 1.1 % of reading + 0.84 lbf·in 1.1 % of reading + 9.1 lbf·in	Comparison to Torque Wrench Calibration System
Torque Analyzers, Torque Transducers ¹	(2.5 to 25) lbf·in (25 to 250) lbf·in (100 to 1 000) lbf·in (300 to 3 000) lbf·in (100 to 1 200) lbf·ft	0.4 % of reading 0.004 % of reading + 0.13 lbf·in 0.06 % of reading + 0.066 lbf·in 0.04 % of reading + 0.11 lbf·in 0.024 % of reading + 0.07 lbf·ft	Comparison to NIST Class F Weights, Torque Wheel, Torque Arm
Torque Watch Calibrators ¹ Masses	0.5 oz 2 oz 8.5 oz 42.5 oz	0.000 004 oz 0.000 012 oz 0.001 3 oz 0.001 4 oz	Comparison to ASTM E617 Class 1 Weights, Balance
Dial	13.25° 76.75°	0.58° 0.58°	Masses
Hydrometers ^{1,5}	(0.9 to 1) SG (1.2 to 1.4) SG	0.001 7 SG 0.002 9 SG	Comparison to Reference Hydrometer per ASTM E126-19

Photometry and Radiometry

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Gloss Meters ^{1,5}	93.5 GU, 20° 95.4 GU, 60° 99.6 GU, 85°	1.2 GU 0.65 GU 0.58 GU	Per ASTM D523-08 using Gloss Standards
Spectrophotometers Total Hemispherical Diffuse Reflectance ² (8°:t)	(360 to 390) nm (400 to 830) nm	0.37 % of reading 0.27 % of reading	Comparison to Ultra-White Ceramic Reflectance Standard, ΔE CIELAB values reported.
Xenon arc Weathering Instruments ¹ Illuminance (380 to 780) nm	Up to 240 000 lux	4.8 % of reading	Comparison to Atlas XenoCal BST Measure and Calibration Sensor
Xenon arc Weathering Instruments ¹ Irradiance (300 to 800) nm	Up to 1 300 W/m ²	8.2 % of reading	Comparison to Atlas XenoCal 300-800 Measure and Calibration Sensor

Thermodynamic

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Thermometers ¹	(-196 to 0) °C (0 to 420) °C (420 to 660) °C	0.008 % of reading + 0.031 °C 0.001 % of reading + 0.031 °C 0.005 % of reading + 0.01 °C	Comparison to SPRT
Humidity Indicators ¹ (at 23 ± 5 °C)	11 % RH 33 % RH 75 % RH 98 % RH	1.7 % RH 1.5 % RH 1.9 % RH 2.8 % RH	Comparison to Vaisala HMK15 Humidity Calibrator, Accredited Salts
Thermohygrometer Humidity	(10 to 95) % RH	0.16 % of reading + 0.67 % RH	Comparison to Thunder Scientific 1200 Two-Pressure Humidity Generator
Temperature	(10 to 60) °C	0.12 °C	
Radiation (Infrared) Thermometers ¹	35 °C 100 °C 200 °C 350 °C 500 °C	0.47 °C 0.66 °C 0.95 °C 1.7 °C 2.1 °C	Comparison to Fluke 4181 Black Body Source (flat plate) ε = 0.95, λ = (8 to 14) μm



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Thermodynamic

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Radiation (Infrared) Thermometers ¹	100 °C 250 °C 400 °C 550 °C 700 °C 850 °C 982 °C	2.3 °C 2.6 °C 3.4 °C 4 °C 4.8 °C 5.6 °C 6.5 °C	Comparison to Omega BB-4A Black Body Source (cavity) $\epsilon = 0.99, \lambda = (8 \text{ to } 14) \mu\text{m}$
Ovens, Incubators, Stirred Water Baths, Fridges ¹	(0 to 100) °C (0 to 600) °C (-190 to 0) °C (0 to 1 300) °C	0.16 % of reading + 2.8 °C 0.5 % of reading + 2.8 °C 0.07 % of reading + 2.7 °C 0.65 % of reading + 2.8 °C	Comparison to Process Calibrator, Type K Thermocouple Probe
Ovens, Incubators, Stirred Water Baths, Fridges ¹	(-50 to 0) °C (0 to 500) °C	0.8 % of reading + 0.5 °C 0.6 % of reading + 0.5 °C	Comparison to Process Calibrator, Pt 100 RTD Probe
Thermocouples and Thermometers ¹	(-15 to 110) °C (50 to 350) °C (350 to 600) °C	0.41 °C 0.77 °C 0.1 % of reading + 0.25 °C	Comparison to Dry Block Calibrator
Xenon Arc Weathering Instruments ¹ Surface Temperature	(20 to 120) °C	0.084 % of reading + 1.2 °C	Comparison to Atlas XenoCal BST Measure and Calibration Sensor

Time and Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Stopwatches, Timers ¹	Up to 48 h	40 ms	Comparison to Function Generator, Frequency Counter
Stopwatches, Timers ¹	Up to 1 d	53 ms/d	Comparison to Timometer
Frequency – Source ¹	10 mHz to 120 Hz 120 Hz to 1.2 kHz (1.2 to 12) kHz (12 to 120) kHz 120 kHz to 1.2 MHz (1.2 to 2) MHz	13 mHz 0.13 Hz 1.3 Hz 13 Hz 0.13 kHz 1.3 kHz	Comparison to Fluke 5502A Multiproduct Calibrator
Frequency – Source ¹ Sine and Square Triangle and Ramp	100 μHz to 15 MHz 100 μHz to 100 kHz	0.002 5 % of reading 0.002 5 % of reading	Comparison to Agilent 33120A Arbitrary Function Generator

Time and Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Frequency – Source ¹	(2 to 8.4) GHz	12 Hz	Comparison to Anritsu MG3691A RF/Microwave Signal Generator
Frequency – Measure ¹ into 50 Ω load into 1 MΩ load into 50 Ω load	(10 to 525) MHz 10 Hz to 80 MHz (10 to 100) MHz (0.1 to 1) GHz (1 to 10) GHz (10 to 20) GHz	10.7 mHz/Hz + 1.8 Hz 19.3 nHz/Hz + 1.2 Hz 1.2 Hz/MHz + 1 Hz 0.12 kHz/GHz + 1 Hz 1.2 kHz/GHz + 1 Hz 8 kHz/GHz + 1 Hz	Comparison to HP 5350B Frequency Counter
Frequency – Measure ¹	10 Hz to 10 MHz	0.013 % of reading + 5 mHz	Comparison to Keysight 3458A 8.5 Digit Multimeter
Frequency – Time Based Aging ¹	10 MHz	1 pHz/Hz	Comparison to Fluke 910R GPS Controlled Atomic Clock
Rotational Viscometers ^{1,5}	(2 to 2 000) rpm	1.5 rpm	Comparison to Optical Tachometer
Crosshead Speed ¹	(0.2 to 2) in/min	0.07 % of reading + 0.005 3 in/min	Stopwatch, Depth Indicator; ASTM E2658 utilized in the calibration of this parameter.
Non-contact Tachometer ^{1,5}	(60 to 100 000) rpm	0.025 % of reading	Comparison to Function Generator, LED Light Source
Contact Tachometers ^{1,5}	(10 to 10 000) rpm	0.67 % of reading + 2.5 rpm	Comparison to Tachometer Standard

DIMENSIONAL MEASUREMENT

1 Dimensional

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Dimensional Measurement – 1D ⁵	Up to 12 in (12 to 18) in	(5.5 + 11L) μin (2.7 + 12L) μin	Direct Measure using Universal Length Measuring Machine
Dimensional Measurement – 1D ⁵	Up to 24 in	(260 + 4D) μin	Direct Measure using Vision System
Flatness Measurement ⁵ Up to 4 inD	Up to 100 μin	10 μin	Direct Measure using ZyGo Verifier QPZ Laser Interferometer

3 Dimensional

Parameter / Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method and/or Equipment
Dimensional Measurement – 3D ⁵	X = Up to 18 in Y = Up to 20 in Z = Up to 16 in	(320 + 6L) μin (320 + 6L) μin (320 + 9L) μin	Direct Measure using Coordinate Measuring Machine

TESTING

Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Rockwell Hardness	ASTM E18	HRA, HRB, HRC	Rockwell Hardness Tester
Rockwell Superficial Hardness	ASTM E18	HR15N, HR30N, HR45N, HR15TW, HR30TW, HR45TW	Rockwell Hardness Tester
Brinell Hardness	ASTM E10	BHN	Brinell Hardness Tester
Micro-Hardness	ASTM E384	Knoop, Vickers	Micro-Hardness Tester

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ($k=2$), corresponding to a confidence level of approximately 95%.

- Notes:
1. This laboratory calibration services in its laboratory and on-site at customer-designated locations. Since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
 2. The uncertainty does not include gage R&R study, and the unit under test resolution. Larger measurement uncertainties are expected.
 3. Mismatch uncertainty is not considered in the CMC as it is DUT dependent. Higher uncertainties will be reported based on DUT VSWR.
 4. This calibration is only applicable to the dimensional properties. The metallurgical properties/composition of the test spheres are not tested.
 5. L = length in inches; D = diameter in inches; " = arc-second; DL = diagonal length; GU = gloss unit; rpm = revolutions per minute; SG = specific gravity.
 6. The CMC for scales and balances is highly dependent upon the resolution of the unit under test. The CMC presented here does not include the resolution of the unit under test. The resolution will be included in the reported measurement uncertainty at the time of calibration.
 7. The values in the Range column are Nominal values. The actual certified values will be used at the time of calibration, along with the associated measurement Uncertainty.
 8. Unless otherwise specified in the far-right hand column, the calibration procedure/method was written internally.
 9. This scope is formatted as part of a single document including Certificate of Accreditation No. ACT-1886.



Jason Stine, Vice President

